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Optoelectronic Measurement Technology and Systems

**Jigui Zhu
Hwa-Yaw Tam
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Editors

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Introduction

The optoelectronic principle plays an outstanding role in the field of metrology and testing areas, as it provides an important method for the development of measurement technology. With the rapid development of information and measurement technology, systems that obtain sources of information have drawn much attention. New measurement requirements appear constantly, which promote continuous development of the optoelectronic measurement method, technology, and application, as well as bring vigor and vitality to the research on optoelectronic measurement.

Optoelectronic measurement research covers a range of content, from scientific research to that of the manufacturing industry and daily life. The aim will be to continue expanding and gathering content. Traditional optoelectronic measurement research and applications have been consistently improving in the field of industrial manufacturing precision measurement technology and concerned performances. Furthermore, the needs of optoelectronic measurement represented in the measurement of digital cultural heritage and environment protection have been emerging ceaselessly alongside the development of measuring methods and applications.

A total of 53 papers are included in these proceedings from the Optoelectronic Measurement Technology and System branch of OIT' 2015. The papers apply to research fields including: optoelectronic measurement, optical instruments, industrial measurement, grating projection, spectral measurement, and optical fiber measurement. These papers appropriately reflect the current focus and research level of the optoelectronic measurement field.

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